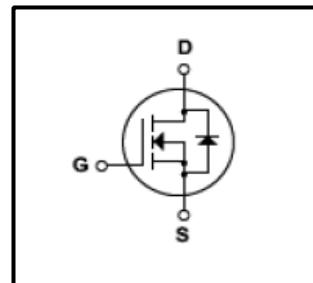
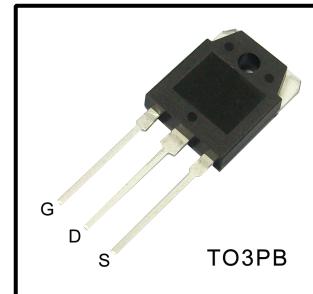


Silicon N-Channel MOSFET
Features

- 18A,500V, $R_{DS(on)}$ (Max0.27Ω)@ $V_{GS}=10V$
- Ultra-low Gate charge(Typical 42nC)
- Fast Switching Capability
- 100%Avalanche Tested
- Maximum Junction Temperature Range(150°C)


General Description

This Power MOSFET is produced using Winsemi's advanced planar stripe,VDMOS technology.this latest technology has been especially designed to minimize on-state resistance, have a high rugged avalanche characteristics .This devices is specially wellsuited for AC-DC switching power supplies, DC-DC power Converters high voltage H-bridge motor drive PWM


Absolute Maximum Ratings

Symbol	Parameter	Value	Units
V_{DSS}	Drain Source Voltage	500	V
I_D	Continuous Drain Current(@ $T_c=25^\circ C$)	18	A
	Continuous Drain Current(@ $T_c=100^\circ C$)	12.7	A
I_{DM}	Drain Current Pulsed	(Note1)	A
V_{GS}	Gate to Source Voltage	± 30	V
E_{AS}	Single Pulsed Avalanche Energy	(Note2)	mJ
E_{AR}	Repetitive Avalanche Energy	(Note1)	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note3)	V/ns
P_D	Total Power Dissipation(@ $T_c=25^\circ C$)	208	W
T_J	Junction Temperature	150	°C
T_{stg}	Storage Temperature	-55~150	°C
T_L	Channel Temperature	300	°C

Thermal Characteristics

Symbol	Parameter	Value			Units
		Min	Typ	Max	
R_{QJC}	Thermal Resistance , Junction -to -Case	-	-	0.60	°C/W
R_{QJA}	Thermal Resistance , Junction-to -Ambient	-	-	40	°C/W

Electrical Characteristics(Tc=25°C)

Characteristics	Symbol	Test Condition	Min	Type	Max	Unit	
Gate leakage current	I_{GSS}	$V_{GS}=\pm 25V, V_{DS}=0V$	-	-	± 10	nA	
Gate-source breakdown voltage	$V_{(BR)GSS}$	$I_G=10 \mu A, V_{DS}=0V$	± 30	-	-	V	
Drain cut -off current	I_{DSS}	$V_{DS}=500V, V_{GS}=0V$	-	-	100	μA	
Drain -source breakdown voltage	$V_{(BR)DSS}$	$I_D=10 mA, V_{GS}=0V$	500	-	-	V	
Breakdown voltage Temperature coefficient	$\triangle BV_{DSS}/\triangle T_J$	$I_D=250\mu A$, Referenced to 25°C	-	0.5	-	V/°C	
Gate threshold voltage	$V_{GS(th)}$	$V_{DS}=10V, I_D=1mA$	3	-	5	V	
Drain -source ON resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D=9A$	-	0.23	0.27	Ω	
Forward Transconductance	g_{fs}	$V_{DS}=40V, I_D=9A$	-	16	-	S	
Input capacitance	C_{iss}	$V_{DS}=25V,$ $V_{GS}=0V,$ $f=1MHz$	-	2530	3290	pF	
Reverse transfer capacitance	C_{rss}		-	11	14.3		
Output capacitance	C_{oss}		-	300	390		
Switching time	Rise time	t_r	$V_{DD}=250V,$ $I_D=18A$ $R_G=25\Omega$ (Note4,5)	-	40	90	ns
	Turn-on time	t_{on}		-	150	310	
	Fall time	t_f		-	95	200	
	Turn-off time	t_{off}		-	110	230	
Total gate charge(gate-source plus gate-drain)	Q_g	$V_{DD}=400V,$ $V_{GS}=10V,$ $I_D=18A$ (Note4,5)	-	42	55	nC	
Gate-source charge	Q_{gs}		-	12	-		
Gate-drain("miller") Charge	Q_{gd}		-	14	-		

Source-Drain Ratings and Characteristics(Ta=25°C)

Characteristics	Symbol	Test Condition	Min	Type	Max	Unit
Continuous drain reverse current	I_{DR}	-	-	-	18	A
Pulse drain reverse current	I_{DRP}	-	-	-	72	A
Forward voltage(diode)	V_{DSF}	$I_{DR}=18A, V_{GS}=0V$	-	-	1.4	V
Reverse recovery time	t_{rr}	$I_{DR}=18A, V_{GS}=0V,$ $dI_{DR} / dt = 100 A / \mu s$	-	500	-	ns
Reverse recovery charge	Q_{rr}		-	5.4	-	μC

Note 1.Repeativity rating :pulse width limited by junction temperature

2.L=5.2mH $I_{AS}=18A, V_{DD}=50V, R_G=25\Omega$,Starting $T_J=25^\circ C$

3. $I_{SD}\leq 18A, di/dt\leq 200A/\mu s, V_{DD}<BV_{DSS}$,STARTING $T_J=25^\circ C$

4.Pulse Test:Pulse Width $\leq 300\mu s$,Duty Cycle $\leq 2\%$

5. Essentially independent of operating temperature.

This transistor is an electrostatic sensitive device

Please handle with caution

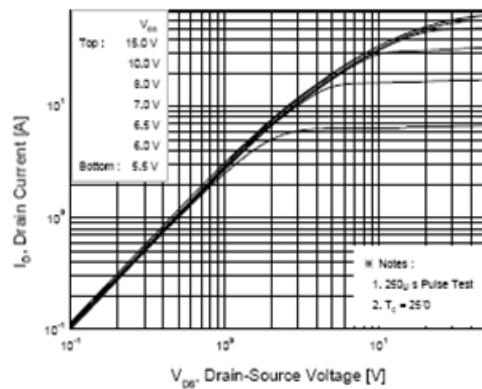


Fig.1 On State Characteristics

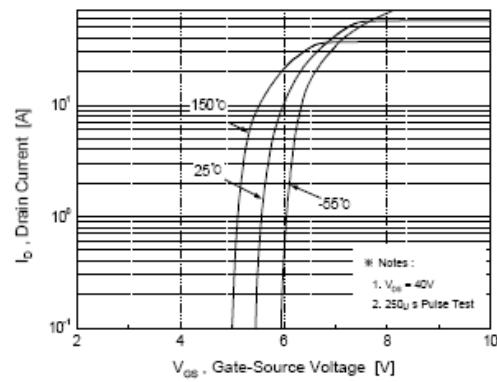


Fig.2 Transfer Current Characteristics

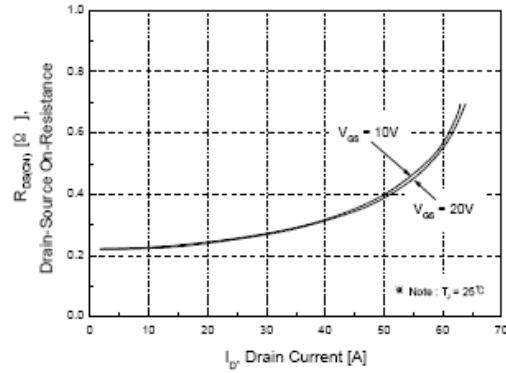


Fig.3 On-Resistance Variation vs Drain Current

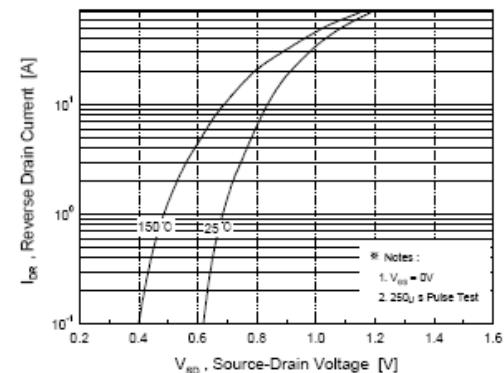


Fig.4 Body Diode Forward Voltage Variation with Source Current and Temperature

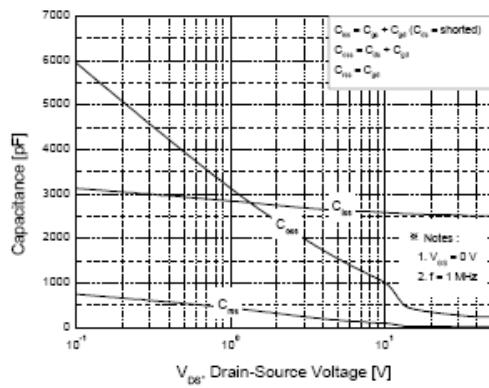


Fig.5 Capacitance Characteristics

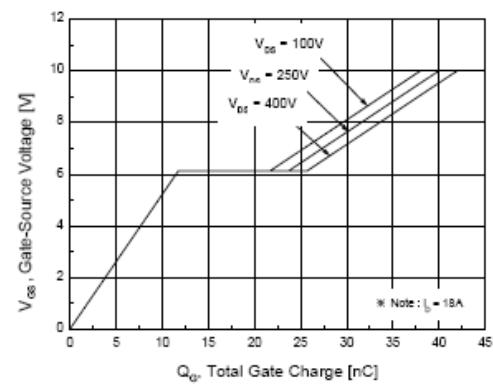


Fig.6 Gate Charge Characteristics

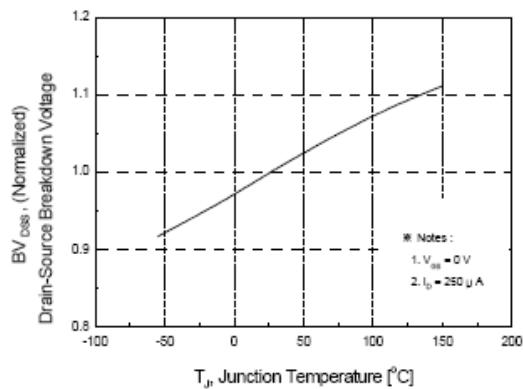
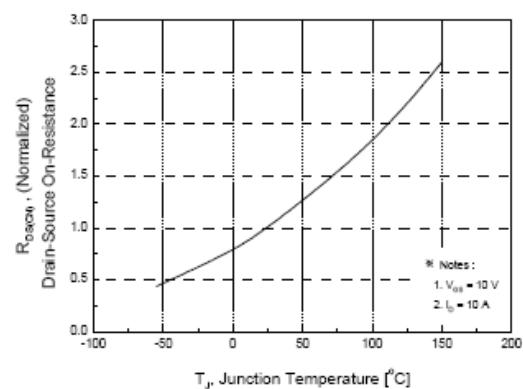


Fig.7 Breakdown Voltage Variation



**Fig.8 On-Resistance Variation
vs.Temperature**

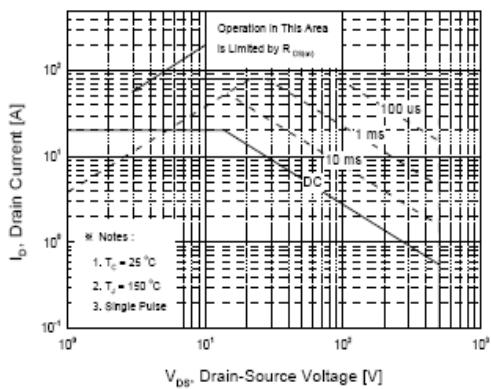
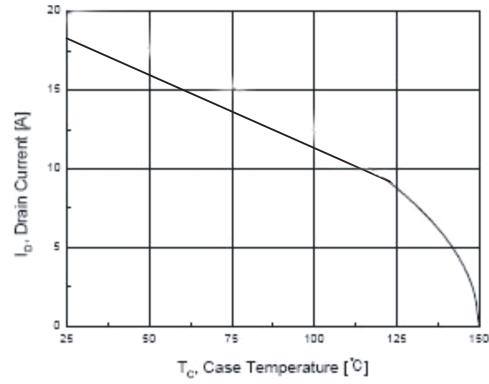


Fig.9 Maximum Safe Operation Area



**Fig.10 Maximum Drain Current vs
Case Temperature**

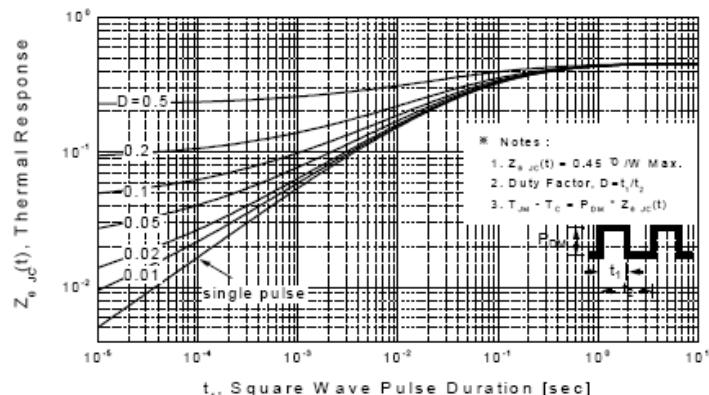


Fig.11 Transient Thermal Response Curve

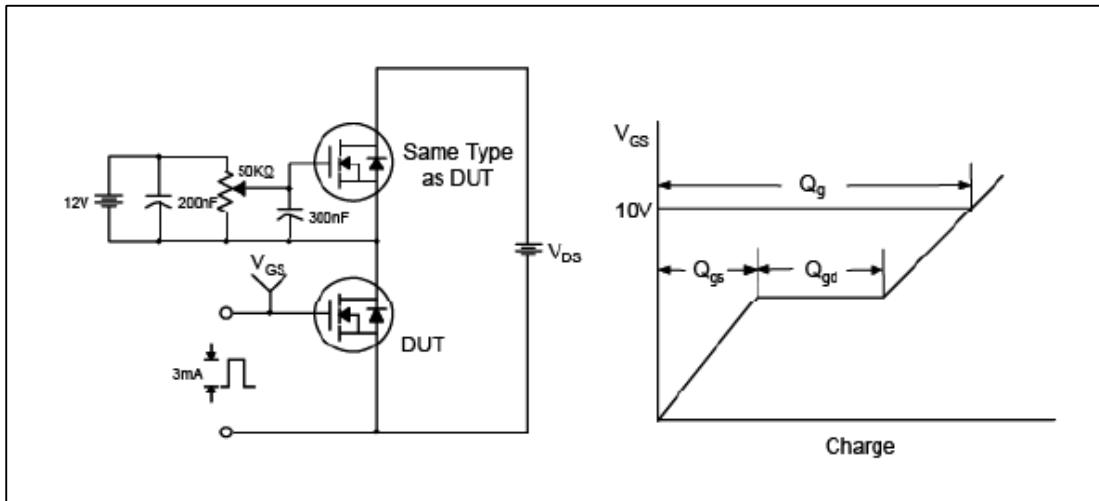


Fig.12 Gate Test Circuit & Waveform

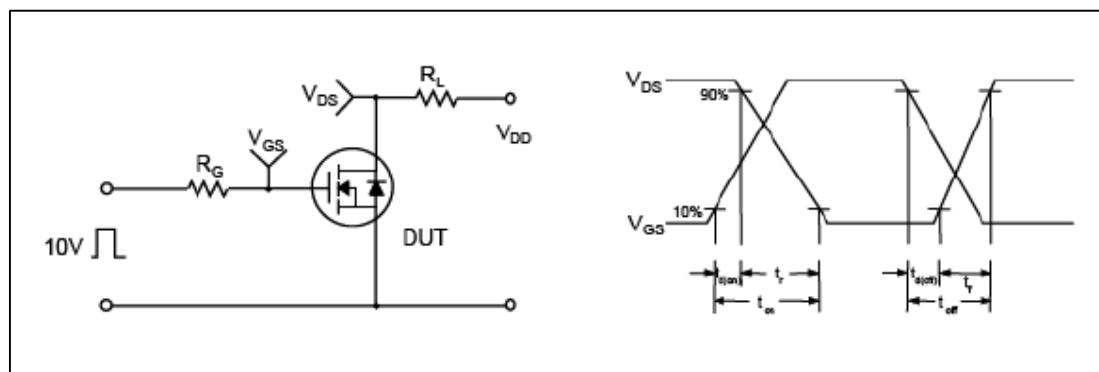


Fig.13 Resistive Switching Test Circuit & Waveform

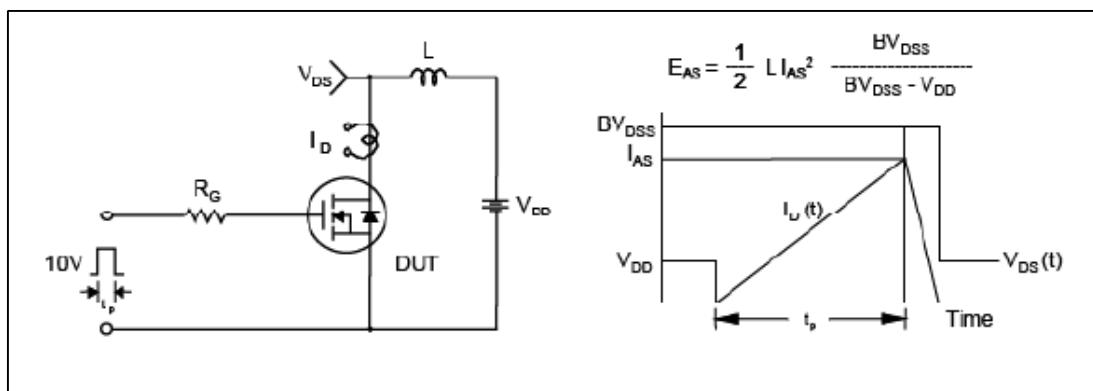


Fig.14 Unclamped Inductive Switching Test Circuit & Waveform

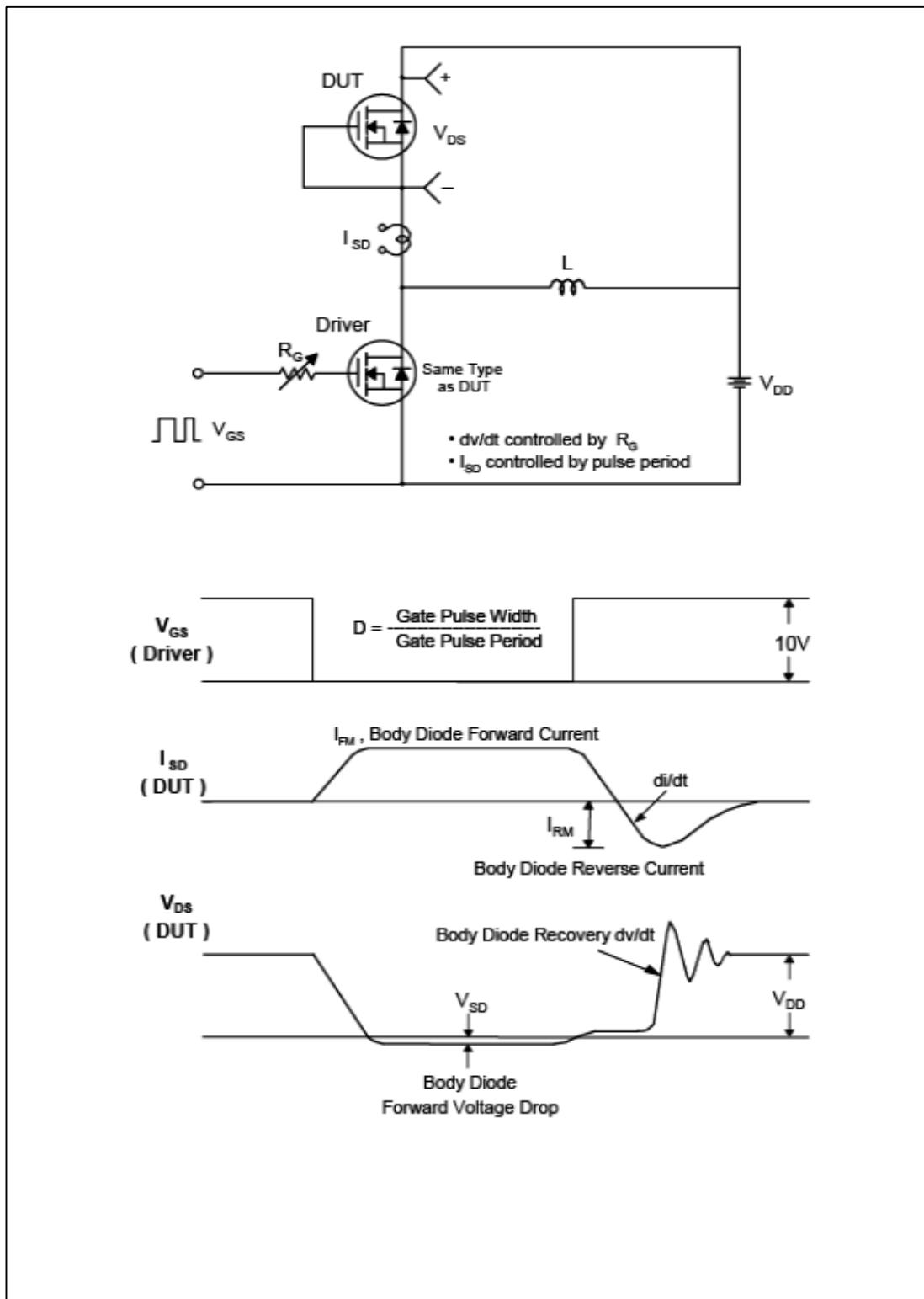


Fig.15 Peak Diode Recovery dv/dt Test Circuit & Waveform

TO-3PB Package Dimension

